Se	earch	Notes	
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Application/Control No.	Applicant(s)/Patent under Reexamination
10/743,670	MURRAY, MATT
Examiner	Art Unit
Yuwen Pan	2618

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SEARCHED				
Class	Subclass	Date	Examiner	
455	550.1,575. 1,90.3	11/21/2006	YP	
381	71.1			
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH	TES STRATEGY	)
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XU MEI (RESTRICTION AND SEARCH)	11/21/2006	ΥP
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